

09831525_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 09831525 on July 29, 2003

Original Classifications

3	324/765
3	714/724
3	714/732
3	714/736
2	714/712
2	714/718
2	714/726
2	714/738

Cross-Reference Classifications

5	714/733
5	714/734
4	324/537
3	714/724
3	714/732
2	324/501
2	326/81
2	702/59
2	714/720
2	714/726
2	714/727
2	714/736

Combined Classifications

6	714/724
6	714/732
6	714/733
5	714/734
5	714/736
4	324/537
4	324/765
4	714/726
3	714/712
3	714/720
3	714/738
2	324/501
2	324/750
2	326/81
2	702/59
2	714/25
2	714/30
2	714/31
2	714/718

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2 714/719
2 714/727
2 716/4

09831525_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09831525 on July 29, 2003

6	714/724	(3 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
6	714/732	(3 OR, 3 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/732	..Signature analysis
6	714/733	(1 OR, 5 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/733	..Built-in testing circuit (BILBO)
5	714/734	(0 OR, 5 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/734	..Structural (in-circuit test)
5	714/736	(3 OR, 2 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/736	..Device response compared to expected fault-free response
4	324/537	(0 OR, 4 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	324/537	.Of individual circuit component or element
4	324/765	(3 OR, 1 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING

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324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS

324/537 .Of individual circuit component or element

324/765 ..Test of semiconductor device

4 714/726 (2 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/726 ..Scan path testing (e.g., level sensitive sca

n

design (LSSD))

3 714/712 (2 OR, 1 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/712 .Transmission facility testing

3 714/720 (1 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/718 .Memory testing

714/719 ..Read-in with read-out and compare

714/720 ...Special test pattern (e.g., checkerboard,
walking ones)

3 714/738 (2 OR, 1 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/738 ..Including test pattern generator

2 324/501 (0 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS

324/501 .Using radiant energy

2 324/750 (1 OR, 1 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS

324/537 .Of individual circuit component or element

324/750 ..System sensing fields adjacent device under

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test (DUT)

2 326/81 (0 OR, 2 XR)
Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY
326/62 INTERFACE (E.G., CURRENT DRIVE, LEVEL SHIFT,
ETC.)
326/80 .Supply voltage level shifting (i.e., interfac
e
h different between devices of a same logic family wit
operating voltage levels)
326/81 ..CMOS

2 702/59 (0 OR, 2 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/57 .Electrical signal parameter measurement syste
m
702/58 ..For electrical fault detection
702/59 ...Fault location

2 714/25 (1 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
714/1 .Reliability and availability
714/25 ..Fault locating (i.e., diagnosis or testing)

2 714/30 (1 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
714/1 .Reliability and availability
714/25 ..Fault locating (i.e., diagnosis or testing)
714/27 ...Particular access structure
714/30Built-in hardware for diagnosing or testin
g
or test mode within-system component (e.g., microprocess
circuit, scan path)

2 714/31 (1 OR, 1 XR)

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Class	714	:	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
714/100			DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
714/1			.Reliability and availability
714/25			..Fault locating (i.e., diagnosis or testing)
714/27			...Particular access structure
714/31		Additional processor for in-system fault locating (e.g., distributed diagnosis progr

am)

2	714/718		(2 OR, 0 XR)	
	Class	714	:	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699			PULSE OR DATA ERROR HANDLING
	714/718			.Memory testing
2	714/719		(1 OR, 1 XR)	
	Class	714	:	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699			PULSE OR DATA ERROR HANDLING
	714/718			.Memory testing
	714/719			..Read-in with read-out and compare
2	714/727		(0 OR, 2 XR)	
	Class	714	:	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699			PULSE OR DATA ERROR HANDLING
	714/724			.Digital logic testing
	714/726			..Scan path testing (e.g., level sensitive sca
				design (LSSD))
	714/727			...Boundary scan

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2	716/4		(1 OR, 1 XR)	
	Class	716	:	DATA PROCESSING: DESIGN AND ANALYSIS OF CIRCUIT OR SEMICONDUCTOR MASK
	716/1			CIRCUIT DESIGN
	716/4			.Testing or evaluating